

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Shingo Saito

Serial No.: 10/561,280 Group Art Unit: 2886

Filed: 03/19/2007 Examiner: Nguyen, Tu T.

Title: Optical Waveform Measurement Device and Measurement Method thereof, Complex Refractive Index Measurement Device and Measurement Method Thereof, and Computer Program Recording Medium Containing the Program

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

SUPPLEMENTARY RESPONSE AND AMENDMENT UNDER 37 CFR §1.121

Dear Sir or Madam:

This paper is filed as a supplement to the response filed on February 1, 2010, to the Office Action mailed October 1, 2009. A request for an extension of time of one month was submitted with the February 1 response.

Amendments

Please amend the above-identified U.S. application as follows: